

ABSTRACT:

An electronic circuit device has contact terminal outside its package. The contact terminals are connected via the main current channels of two transistors connected in parallel between the contact terminals, so as to provide a switchable short circuit between the terminals. The device is tested by connecting two sense contacts of a resistance measuring device to the terminals and measuring the resistance between the sense contacts a first, second and third state respectively, the first and second transistor being switched on and off respectively in the first state and vice versa in the second state, both transistors being switched on in the third state. The resistance in the three states is modeled as a model resistance composed of a series resistance component in series with a first resistance component, a second resistance component and a parallel arrangement of said first and second resistance component respectively. The series resistance component is eliminated in tests of the device to avoid the effect of an unstable contact resistance between the terminals and the sense contacts.

Fig. 1